



**HAL**  
open science

# Planar and Transparent Memristive Devices Based on Titanium Oxide Coated Silver Nanowire Networks with Tunable Switching Voltage

Joao Resende, Abderrahime Sekkat, Viet Huong Nguyen, Tomy Chatin, Carmen Jiménez, Mónica Burriel, Daniel Bellet, David Munoz-Rojas

► **To cite this version:**

Joao Resende, Abderrahime Sekkat, Viet Huong Nguyen, Tomy Chatin, Carmen Jiménez, et al.. Planar and Transparent Memristive Devices Based on Titanium Oxide Coated Silver Nanowire Networks with Tunable Switching Voltage. *Small*, 2021, 17 (21), pp.2007344. 10.1002/sml.202007344 . hal-03286501

**HAL Id: hal-03286501**

**<https://hal.univ-grenoble-alpes.fr/hal-03286501>**

Submitted on 14 Jul 2021

**HAL** is a multi-disciplinary open access archive for the deposit and dissemination of scientific research documents, whether they are published or not. The documents may come from teaching and research institutions in France or abroad, or from public or private research centers.

L'archive ouverte pluridisciplinaire **HAL**, est destinée au dépôt et à la diffusion de documents scientifiques de niveau recherche, publiés ou non, émanant des établissements d'enseignement et de recherche français ou étrangers, des laboratoires publics ou privés.

## Planar and Transparent Memristive devices based on Titanium Oxide coated Silver Nanowire Networks with Tunable Switching Voltage

Joao Resende,<sup>1,2</sup> Abderrahime Sekkat,<sup>1</sup> Viet Huong Nguyen,<sup>3</sup> Tomy Chatin,<sup>1</sup> Carmen Jiménez,<sup>1</sup> Mónica Burriel,<sup>1</sup> Daniel Bellet<sup>1\*</sup>, David Muñoz-Rojas<sup>1\*</sup>

<sup>1</sup> Univ. Grenoble Alpes, CNRS, Grenoble INP, LMGP, F-38000 Grenoble, France

<sup>2</sup> AlmaScience, Campus da Caparica, Almada, Portugal

<sup>3</sup> Faculty of Electrical and Electronic Engineering, Phenikaa University, Hanoi, Vietnam

Corresponding authors: daniel.bellet@grenoble-inp.fr and david.munoz-rojas@grenoble-inp.fr

Keywords: Resistive Switching, Nanocomposite, TiO<sub>2</sub>, AgNW

Threshold Switching devices are fundamental active elements in More than Moore approaches, integrating the new generation of non-volatile memory devices. Here, we report an in-plane threshold resistive switching device with an on/off ratio above 10<sup>6</sup>, a Low Resistance State of 10 to 100 kΩ and a High Resistance State of 10 to 100 GΩ. Our devices are based on nanocomposites of silver nanowire networks and titanium oxide, where volatile unipolar threshold switching takes place across the gap left by partially spheroidized nanowires. Device reversibility depends on the titanium oxide thickness, while nanowire network density determines the threshold voltage, which can reach as low as 0.16 V. The switching mechanism is explained through percolation between metal-semiconductor islands, in a combined tunneling conduction mechanism, followed by a Schottky emission generated via Joule heating. The devices are prepared by low-cost, atmospheric pressure, and scalable techniques, enabling their application in printable, flexible and transparent electronics.

### 1. Introduction

The interest by the microelectronics industry to evolve from charge storage to resistance change devices has boosted the research activities in resistive switching (RS), both in terms of materials and on possible device structures<sup>[1-3]</sup>. A resistive switching component or memristive device presents a variable resistance that can be controlled by applying a current or voltage<sup>[1,4]</sup>. In the case of threshold switching (TS), the resistance change is volatile, as one of the resistance states is only maintained while the electrical stimulus is preserved<sup>[1]</sup>. These TS components are

1  
2  
3  
4  
5  
6  
7  
8  
9  
fundamental as selectors to avoid the propagation of leakage current in non-volatile memory  
devices<sup>[1]</sup> and for applications in neuromorphic computation systems<sup>[5]</sup>. Research in resistive  
switching has been further intensified to create transparent and even flexible devices, in order  
to produce fully integrated transparent circuits compatible with roll-to-roll technologies and  
printed electronics<sup>[6]</sup>.

10  
11  
12  
13  
14  
15  
16  
17  
18  
19  
20  
21  
22  
23  
24  
25  
26  
27  
28  
29  
30  
31  
32  
33  
34  
35  
36  
37  
38  
39  
40  
41  
42  
43  
44  
45  
46  
47  
48  
49  
The combination of metallic nanowire networks with oxide thin films has been quite  
successful in the creation of stable transparent and flexible electrodes for many different  
applications, such as transparent heaters<sup>[7,8]</sup>, photovoltaics<sup>[9]</sup>, efficient lighting<sup>[10]</sup> or smart  
windows<sup>[11]</sup>. Different metallic networks based on silver nanowires (AgNWs) have also been  
applied in memristive devices in both planar<sup>[12–17]</sup> and vertical configurations<sup>[18–20]</sup>. These  
nanowire-based devices present two different switching mechanisms: conductive filament  
formation and tunneling mechanism. Concerning the first mechanism, Du et al.<sup>[15]</sup> showed TS  
of silver@AgO core-shell nanowire networks under an applied voltage. Conductive filaments  
are created at the junctions between nanowires thanks to the migration of silver atoms from the  
Ag core through the AgO shell. A TS mechanism was proposed by Yeom et al.<sup>[18]</sup>, where a  
vertical Ag filament is formed between a AgNWs bottom electrode and a platinum top electrode,  
using titanium dioxide (TiO<sub>2</sub>) both as an insulator and TS medium. In both studies, Joule  
heating is claimed as the cause of the transition from the Low Resistance State (LRS) to the  
High Resistance State (HRS) at close to zero bias. However, the formed filaments would remain  
upon cooling (i.e. reduction in the applied voltage), therefore preserving the LRS. Wan et al.<sup>[19]</sup>  
have proposed an alternative mechanism to create a TS device based on the controlled  
fragmentation of AgNWs in devices fabricated using top contacts. In this case, the conduction  
through isolated fragments of the network is possible due to tunneling between closely spaced  
silver nanoparticles (AgNPs) between the nanowires and the top contacts, as reported also by  
Sun et al.<sup>[21]</sup>. In this mechanism, the existence of a potential barrier between the nanoparticles  
accounts for both the transition from the LRS to the HRS at low voltages and the volatile nature  
of the switching.

50  
51  
52  
53  
54  
55  
56  
57  
58  
59  
60  
61  
62  
63  
64  
65  
In our group, the fragmentation and consequent spheroidization of silver nanowires have  
been intensively studied during stability tests of electrodes under thermal<sup>[22,23]</sup> and electrical  
stress<sup>[24,25]</sup>. Importantly, we found that when subjected to a voltage ramp, the resulting network  
breakdown is a highly correlated and spatially localized phenomenon, where the silver  
nanowires spheroidize into nanoparticles in a small (i.e. microns) longitudinal region parallel  
to the electrodes<sup>[24]</sup>. After such a degradation of the network, new conductive pathways can

1 appear when an electrical potential is reapplied<sup>[24]</sup>. The creation of this conductive state between  
2 the electrodes yields networks that are two orders of magnitude more resistive than the pristine  
3 ones<sup>[24]</sup>. This phenomenon is not yet fully understood and it was proposed to be related to the  
4 diffusion of silver atoms<sup>[24]</sup>, as the conduction pathways between the metallic nanoparticles are  
5 discrete and localized in specific regions where the nanowires spheroidized.  
6  
7

8  
9 In this study, we further explored this phenomenon and tuned the electrical breakdown of  
10 AgNW networks coated with a TiO<sub>2</sub> thin film to create memristive devices based on threshold  
11 switching. We report the effect of both network density and oxide coating thickness on the TS  
12 phenomenon, and propose a switching mechanism based on a combination of electron tunneling  
13 and Schottky emission along conductive paths made of bare and coated silver nanoparticles.  
14 The innovative transparent nanocomposite structure deposited on a glass substrate is based on  
15 localized degradation of nanowire networks, which enables planar and miniaturized TS devices  
16 as no top electrode is required. In addition, we use a combination of low-cost, low-temperature  
17 (<150 °C) and scalable technologies, i.e., airbrush spray and atmospheric-pressure spatial  
18 atomic layer deposition (AP-SALD)<sup>[26]</sup>, to fabricate the AgNWs/TiO<sub>2</sub> nanocomposites, which  
19 makes such devices appealing for flexible electronic applications.  
20  
21  
22  
23  
24  
25  
26  
27  
28  
29  
30

## 31 2. Results

32 The different steps for the fabrication of the AgNWs/TiO<sub>2</sub> nanocomposites and the  
33 subsequent electrical stress test are represented in **Figure 1a**, as well as a picture of the as-  
34 fabricated sample in **Figure 1b**. Further information is developed in the Experimental Section.  
35 The resistance of pristine randomly oriented AgNW networks, measured by 2 probes at the  
36 edges of the 5 mm wide samples, varies from 40 to 7 Ω for a corresponding areal mass density  
37 (*amd*) variation from 73 mg/m<sup>2</sup> to 110 mg/m<sup>2</sup>. A SEM micrograph of the silver nanowire  
38 networks with an *amd* of 80 mg/m<sup>2</sup> is presented in **Figure 1c**. The increase in the thickness of  
39 the TiO<sub>2</sub> thin films from 5 to 45 nm caused a resistance increase, reaching 100 Ω for a 45 nm  
40 thick TiO<sub>2</sub> layer and a 73 mg/m<sup>2</sup> areal mass density of the network. A 10 nm thick TiO<sub>2</sub> coating  
41 can be observed in the TEM image shown in **Figure 1d**. The TEM diffraction patterns (Figure  
42 S1 in Supplementary Information) confirm the FCC crystalline silver structure of the AgNWs  
43 and the amorphous nature of the TiO<sub>2</sub> films, as previously reported for thin films deposited  
44 below 200 °C using an AP-SALD system<sup>[27,28]</sup>. The AgNWs/TiO<sub>2</sub> nanocomposite showed an  
45 average transmittance of 67 % in the visible range (390-700 nm), against 87% for the bare  
46 AgNW sample. This variation in transmittance is mainly attributed to the reflection losses due  
47 to the thin TiO<sub>2</sub> layer (Figure S2 in Supplementary Information).  
48  
49  
50  
51  
52  
53  
54  
55  
56  
57  
58  
59  
60  
61  
62  
63  
64  
65

**Figure 1e** shows the evolution of the resistance for bare and coated networks when subjected to a voltage ramp-up to 15 V. The network densities were 73 and 80 mg/m<sup>2</sup> for the bare nanowire network and for the AgNWs/TiO<sub>2</sub> nanocomposite, respectively, where the oxide layer had a thickness of 10 nm. As expected, the presence of TiO<sub>2</sub> led to a slight increase in resistance from 14.3 Ω for the bare AgNW network to 42.1 Ω for the nanocomposite. As the electrical stress increased during the voltage ramp, a slight increase in resistance was observed for both samples due to a temperature increase caused by Joule effect<sup>[24]</sup>. At around 12.2 V, the resistance of the electrodes increased sharply due to the formation of a “network-crack”, leading to a loss of electrical percolation<sup>[24]</sup>. The crack is the result of a local spheroidization of the nanowires caused by statistical fluctuations in the network density or the amount of junctions, i.e. fluctuations of the resistance within the network. This creates hot spots in the network, where local temperature can reach above 200 °C<sup>[25]</sup>, leading to the formation of silver nanoparticles with a large dispersion in diameter, from a few nanometers to hundreds nanometers. The detailed mechanism of such a crack formation has been studied and reported previously<sup>[24,25]</sup>. Conversely to the stabilizing effect observed for previously reported nanocomposites made with ZnO<sup>[29,30]</sup>, ZnO:Al<sup>[31]</sup>, ZnO/Al<sub>2</sub>O<sub>3</sub><sup>[32]</sup>, in these experiments both bare AgNW and nanocomposite samples underwent a degradation at rather similar voltage values, although with a lower peak resistance for the coated samples.

Nevertheless, in **Figure 1e**, we can observe that after the formation of the network crack, the resistance decreases above 12 V and current flows through the electrode again while voltage is still applied, between 13 and 15 V. Such “life-after-crack” phenomenon, where a conductive state with a resistance around 1 kΩ is observed in both bare and oxide covered samples, has already been reported in our previous studies.<sup>[24]</sup> Upon application of voltage, current can thus still flow through the crack, generating an average local temperature increase to 40 °C at 15 V, as shown in the IR image presented in the inset of **Figure 1e**.

After this initial crack formation, a successive voltage ramp to 10 V was performed (first half I-V cycle), resulting in the formation of a conductive state, observed for both samples, as put in evidence by the current values above 0.1 mA reached at 10 V, represented in **Figure 2a,b**. Thus the samples undergo a resistance switching from a HRS just after the crack formation to a LRS when a voltage ramp is performed. The HRS is characterized by current values below 10 pA at applied voltages close to zero bias, corresponding to a resistance above 10 GΩ. At the end of the first half cycle, new percolating paths are created, similar to a forming cycle, resulting in a LRS at 10 V with resistance values of 2 kΩ and 200 kΩ, for the bare AgNWs and the

nanocomposite. These conductive states are characterized by high current values above 50  $\mu\text{A}$ , even if the resistance values are higher than for pristine samples. This LRS obtain has a higher resistance than the one obtained after the initial crack formation **Figure 1e** at 15V. This is due to the different voltage bias applied, as well as the different voltage rate.

The samples were then subjected to a series of negative and positive voltage ramps (from 10 V to -10 V and -10 V to 10 V, respectively). The bare nanowire networks did not show any switching behavior, shown in **Figure 2a**, as the network maintains a conductive state with a resistance above 1 k $\Omega$ . Conversely, for the AgNWs/TiO<sub>2</sub> nanocomposite, the application of two cycles resulted in the I-V curves shown in **Figure 2b**, which are typical of a resistive switching behavior. The nanocomposite network thus showed a TS behavior with two well-defined resistance states, LRS and HRS, occurring during each cycle, with resistance values of around 100 k $\Omega$  and 10-100 G $\Omega$ , respectively. Furthermore, a difference in the switching voltage was observed between the transition to LRS and HRS. Indeed, in **Figure 2b** starting from zero bias at HRS (1), the transition to LRS occurs at a certain threshold voltage,  $V_{\text{th}}$ , above 2.5 V (2), and this conductive state is maintained until 10 V (3). While reducing the applied voltage from 10 V, the sample switches from LRS to HRS just before the change in polarization, i.e. close to 0 V (4). The same behavior was observed for the negative sense, with an opposite sign. For the four cycles represented in **Figure 2b**, a  $V_{\text{th}}$  of 3.7  $\pm$  0.5 V with an  $I_{\text{LRS}}/I_{\text{HRS}}$  ratio of  $2.6 \times 10^6$  is observed.

To understand the threshold switching behavior observed in the nanocomposite after generating a network disruption, we studied the influence of the thickness of the TiO<sub>2</sub> layer and the density of the AgNW network on the switching phenomena. The results obtained are summarized in **Figure 3**. Concerning the TiO<sub>2</sub> thickness (5, 15, and 45 nm), we observe the presence of three different behaviors: i) an extremely thin-film of around 5 nm (**Figure 3a**) leads to an unstable TS phenomenon, with a high variability of threshold voltage or even the absence on the LRS to HRS transition, similar to what it is observed in bare AgNW networks. ii) A TiO<sub>2</sub> thickness of 10 to 15 nm allows the formation of LRS and HRS states (**Figure 2b** and **Figure 3b** and **c**). In these cases, the variation of the threshold voltage with TiO<sub>2</sub> thickness is significant:  $3.7 \pm 0.5$  V for 10 nm and  $5.2 \pm 1$  V for 15 nm with similar *amd* values of 73 mg/m<sup>2</sup>. iii) For oxide thickness of around 45 nm, the TS phenomenon is lost and the obtained I-V curve corresponds to a Schottky junction, without any sudden reduction or increase of the current, visible in **Figure 3d**. Therefore, there is an ideal TiO<sub>2</sub> thickness range that yields the

1 TS behavior in this type of memristor devices, corresponding to a TiO<sub>2</sub> thickness between 10  
2 and 15 nm in our case.

3  
4 The effect of network density on the switching is presented in **Figure 3b** and **c**, where  
5 nanocomposites made with networks having *amd* values of 73 mg/m<sup>2</sup> and 109 mg/m<sup>2</sup> coated  
6 with a 15 nm thick TiO<sub>2</sub> film present different threshold voltages of 5.2 ± 1 V and 0.16 ± 0.03  
7 V, respectively. The corresponding I<sub>LRS</sub>/I<sub>HRS</sub> ratios were 3.7x10<sup>6</sup> and 8.2 x10<sup>6</sup>. The lower initial  
8 resistance of the denser networks (13.7 Ω), when compared to the sparse networks (30.8 Ω),  
9 could explain the reduction of the threshold voltage, as well as favoring a higher reproducibility  
10 in the TS transitions, similar to other devices based on nanowire networks<sup>[33]</sup>. Similarly, the  
11 localized crack area contributes to the extremely low threshold voltages obtained. Moreover,  
12 these results are reproducible, as shown in Figure S3 of Supporting Information, which presents  
13 further IV curves for the different nanocomposite devices, showing similar behavior to the ones  
14 in **Figure 2** and **Figure 3**.  
15  
16  
17  
18  
19  
20  
21  
22  
23

24 The morphological and compositional analyses of the nanocomposites obtained by SEM  
25 are fundamental to understand the changes of the AgNWs/TiO<sub>2</sub> network in the crack region,  
26 responsible for the TS behavior. These results are presented for bare networks and for  
27 nanocomposites made with TiO<sub>2</sub> layers (15 and 45 nm thick) in **Figure 4a, b** and **c**. The images  
28 show an overall view of the region containing the localized crack (on the left), and a magnified  
29 view of the damaged region (on the right). The difference in contrast observed in these  
30 secondary electrons SEM images is due to the charge effect induced by different conduction  
31 between the pristine nanowires with low resistance, and the high resistance of the AgNW and  
32 TiO<sub>2</sub> composite in the crack region. The crack region is limited to a width of around 20 μm,  
33 spanning through the whole 5 mm length of the sample, visible in both **Figure 4a and b**, while  
34 the non-damaged nanowires are observable on the sides. The contrast is less visible in the 45  
35 nm thickness TiO<sub>2</sub> case in **Figure 4c**. When observing in detail the crack region of the bare  
36 AgNWs, we see that the AgNWs are degraded, leading to the appearance of large silver particles  
37 recognized by a higher brightness in the image. A closer view on the AgNWs/TiO<sub>2</sub>  
38 nanocomposite allows identifying the TiO<sub>2</sub> coating still present around the silver nanowires that  
39 endured the electrical breakdown (**Figure 4b** and **c**). In Figure S4 of Supporting Information,  
40 an EDS mapping of Ti and Ag is presented, showing a Ti presence homogeneously throughout  
41 the sample, while Ag was mainly detected on the pristine nanowires out of the crack region and  
42 in round particles in the crack region. Two kinds of grains are observed in these images: bright  
43 and large ones, which correspond to spherical silver nanoparticles aligned along the path of the  
44  
45  
46  
47  
48  
49  
50  
51  
52  
53  
54  
55  
56  
57  
58  
59  
60  
61  
62  
63  
64  
65

previously existing nanowire; the other grains are dark and small, corresponding to TiO<sub>2</sub> nanoparticles formed from the TiO<sub>2</sub> thin film on the substrate. It was not possible to determine whether these TiO<sub>2</sub> nanoparticles are still amorphous or have crystallized due to the heat produced during the formation of the crack. Finally, for a TiO<sub>2</sub> thickness to 45 nm the degradation of the AgNW network is clearly reduced when compared to the previous examples. In this case, we assume that the presence of a thicker TiO<sub>2</sub> oxide layer contributes as a conductive medium for current passage, justified by the Schottky behavior of **Figure 3d**, while at the same time limits the morphological changes in the silver nanowires, as visible in the crack region in **Figure 4c**.

### 3. Discussion and Threshold Switching Model

Previous studies have shown that the deposition of a thin oxide coating on AgNW networks provides thermal and electrical stabilization of the same thanks to hindered Ag diffusion through the oxide layer<sup>[30]</sup>. In **Table 1**, we present the performance of different threshold switching devices based on silver nanowires reported in the literature, comparing the medium, structure, On/Off ratio, and threshold voltage. As shown in the table, our devices show the best performance among the reported planar devices based on AgNWs.

*Table 1 Silver nanowire-based threshold switching devices reported in the literature, in terms of medium, structure, On/Off ratio, and threshold voltage*

Threshold Switching medium	Structure	On/Off ratio	V <sub>th</sub> (V)	Ref
AgNW/TiO <sub>2</sub> core-shell	Single nanowire	10 <sup>7</sup>	0.4-0.6	Manning et al., 2017 <sup>[34]</sup>
AgNW/AgO <sub>x</sub> core-shell	Planar	100	~0.1 - 3	Du et al., 2017 <sup>[15]</sup>
PI/AgNWs/TiO <sub>2</sub> /Pt	Vertical	200	1.1	Yeom et al., 2017 <sup>[18]</sup>
AgNWs/AgO <sub>x</sub> /AgNWs	Planar	5x10 <sup>5</sup>	0.5 - 20	Wan et al., 2018 <sup>[19]</sup>
AgNW and TiO <sub>2</sub> NPs	Planar	-	>100	Li et al., 2020 <sup>[17]</sup>
AgNWs/TiO <sub>2</sub> core-shell	Vertical	10 <sup>6</sup>	0.1	Kim et al., 2020 <sup>[35]</sup>
AgNWs/TiO <sub>2</sub>	Planar	10 <sup>6</sup>	0.16 - 5.2	This work

Conversely, the AgNW/TiO<sub>2</sub> nanocomposites studied here undergo localized degradation at similar voltages than bare AgNW networks, through the formation of a crack upon application of an electrical stress in the form of a voltage ramp. As a result, three different types of structures can be observed within the crack: elongated AgNWs nanoparticles coated by TiO<sub>2</sub>, round bare Ag nanoparticles (i.e. outside the TiO<sub>2</sub> shell), and TiO<sub>2</sub> nanoparticles having a



1 diameter below 10 nm. The formation of these nanostructures within the crack generates a  
2 localized region of 20  $\mu\text{m}$  that presents volatile unipolar TS behavior, as it is independent on  
3 the voltage polarity and only one HRS is observed at close to zero bias. Still, the  
4 nanocomposites presented here would require further processing, such as the deposition of an  
5 encapsulation layer, in order to ensure a stable TS performance of the Ag and  $\text{TiO}_2$   
6 nanostructures in the localized crack region.  
7  
8  
9

10  
11 We observed that the RS only takes place for  $\text{TiO}_2$  coatings of a certain thickness, 10 to  
12 15 nm in our case. For bare networks or for networks coated with  $\text{TiO}_2$  films with thickness  
13 below 10 nm, the migration of silver atoms results in electrical conduction pathways, yielding  
14 a LRS regardless of the applied voltage, even at applied voltages close to zero bias. In these  
15 cases, the RS behavior cannot be tuned with the applied voltage. This observation disagrees  
16 with the commonly reported conductive filament mechanism, in which a transition from LRS  
17 to HRS would take place due to the filament being disrupted by Joule heating<sup>[15],[18]</sup>. When a  
18 40 nm thick  $\text{TiO}_2$  coating is present, the diffusion of silver is hindered and most silver  
19 nanoparticles in the crack are still surrounded by a thick layer of insulating  $\text{TiO}_2$ , as can be seen  
20 in **Figure 4c**. This would prevent an ohmic electrical transport, resulting in the formation of a  
21 Schottky junction between  $\text{TiO}_2$  and Ag, as already reported for both silver thin films<sup>[36]</sup> and  
22 nanowires<sup>[37]</sup>. Thus, for intermediate thicknesses of 10-15 nm, the crack region would contain  
23 both bare and coated AgNPs in which the coating would be thin enough to allow the pass of  
24 current upon application of a voltage (see scheme in **Figure 5a**). This clearly implies that the  
25  $\text{TiO}_2$  plays a key role in the switching behavior, both affecting the diffusion of Ag atoms during  
26 the electrical breakdown, and by tuning the electric contact between silver nanoparticles due to  
27 the insulating nature of the oxide. These results also imply that the previously proposed  
28 mechanism for systems composed of a metal and an oxide thin film purely based on the  
29 formation of silver filaments across the  $\text{TiO}_2$  film<sup>[15]</sup> does not apply in our case.  
30  
31  
32  
33  
34  
35  
36  
37  
38  
39  
40  
41  
42  
43  
44  
45  
46

47 In order to gain further insight on the main factors governing the switching mechanism  
48 that takes place in our system, we evaluated the relationship between network density and the  
49 power needed to induce the switching. The electrical power generated dependence with the  
50 applied voltage for different network densities is plotted in **Figure 5b**. Remarkably, we  
51 observed that the threshold switching takes place at similar electrical power values, regardless  
52 of the network density used, represented by the color dots in **Figure 5b**. This fact explains the  
53 reduction of the threshold voltage with the increase of the network density, since denser  
54 networks present a lower resistance and thus a higher current for a given voltage than sparser  
55  
56  
57  
58  
59  
60  
61  
62  
63  
64  
65

networks. It can also be observed that in all cases the electrical power consistently changes from around 1 nW to 100  $\mu$ W upon switching from HRS to LRS. When reversing the voltage ramp, the LRS is in all cases lost when the electrical power is reduced to around 10 pW. **Figure 5b** also shows the switching cycles for networks coated with different TiO<sub>2</sub> thicknesses (10 vs. 15 nm). As can be seen, the thickness of the coating has no direct effect on the power.

The fact that the switching happens in all cases at similar power values would imply that is governed by the heat-induced by the Joule effect. As a consequence, we propose a TS mechanism based on two different phenomena: i) electron tunneling over the physical distance of extremely close silver nanostructures (including coated ones) and ii) conduction through the isolating shell of TiO<sub>2</sub> by Schottky emission<sup>[38]</sup>. As the applied voltage increases, starting from zero bias at the HRS, the transition to the LRS occurs at a certain threshold voltage due to an abrupt electron tunneling between close silver nanoparticles and nanowires. As the temperature of the system increases due to Joule heating, thermally-activated electrons can be injected over the energy barrier of the TiO<sub>2</sub> conduction band allowing a Schottky emission<sup>[38]</sup> through the oxide shell. Once Schottky emission starts taking place, it induces a further Joule heating, thus developing a chain reaction process that yields a sharp increase in current. This allows a stable conductive state after the switching until the maximum voltage value of the cycle is reached. When the voltage ramp is reversed, the conductive state is maintained as the Schottky barrier between TiO<sub>2</sub> and Ag is already overcome, i.e. the activated electrons are still mobile. Nevertheless, as the voltage keeps decreasing and reaches values close to zero bias, the conductive state is lost as electrons cannot pass through the potential barrier anymore. This state is created by a decrease in the flow of electrons from TiO<sub>2</sub> and AgNWs since the cooling down effect reduces the probability of electrons to overcome the Schottky potential barrier and thus the conduction is lost, reaching the HRS. The combination of electron tunneling and Schottky emission has already been reported in resistive switching devices systems<sup>[39,40]</sup>, nevertheless, the combined mechanisms have never been used to describe a TS device of silver nanowires, to the best of our knowledge. Furthermore, the Schottky emission mechanism is characterized by the following relationship between current,  $I$ , and voltage,  $V$ :

$$\ln(I) \propto \frac{q}{k_b T} \sqrt{q / 4\pi\epsilon_0\epsilon_r d} \sqrt{V} \quad (1)$$

Where  $q$  is the charge of electron,  $k_b$  is the Boltzmann constant,  $T$  the temperature considered as 300 K,  $\epsilon_0$  the vacuum permittivity, and  $d$  the thickness of the oxide. In **Figure 5c**, we observe the linear dependence of the logarithm of current with the square of the voltage in the LRS region for three different nanocomposites. The linear relation in the LRS confirms the

1 Schottky emission process, showing a slope between 1.1 and 1.3 for the nanocomposites with  
2 a sparse network and a slope of 3.9 for the denser networks. Considering the dielectric constant,  
3  $\epsilon_r$ , of amorphous  $\text{TiO}_2$  reported in the literature, between 13.7<sup>[41]</sup> and 18<sup>[42]</sup>, we can estimate the  
4 thickness of  $\text{TiO}_2$  in the Schottky emission process. For sparse networks, the thickness of the  
5  $\text{TiO}_2$  is estimated to be between 70 and 130 nm. Since a less dense network reduces the amount  
6 of highly conductive metallic structures in the TS region, this would result in a higher electron  
7 conduction through  $\text{TiO}_2$ . As the amount of nanowires increases for the denser networks, the  
8 thickness of the  $\text{TiO}_2$  involved in the conduction is reduced to between 7 and 10 nm. This is  
9 indeed expected, as on average, the oxide contributing to the conduction pathways is diminished  
10 since the amount of silver nanostructures as nanowires and round nanoparticles increase.  
11 Therefore, the electron path will mostly involve the more conductive silver nanostructures.  
12  
13  
14  
15  
16  
17  
18  
19  
20  
21  
22

#### 23 4. Conclusion

24 In conclusion, we have demonstrated that nanocomposites of silver nanowire networks  
25 and titanium oxide thin films present in-plane threshold switching. Optimized devices have  
26  $I_{\text{LRS}}/I_{\text{HRS}}$  ratios above  $10^6$  with threshold voltages as low as 0.16 V. The switching region  
27 consists of silver nanoparticles and titanium oxide shells obtained by the spheroidization of the  
28 AgNWs/ $\text{TiO}_2$  composites having a specific  $\text{TiO}_2$  thickness, 10-15 nm in our case. When low  
29 voltages are applied, the coated network has a high resistance of 10 G $\Omega$  that drastically changes  
30 to a low resistance state of 10 k $\Omega$  above a certain voltage threshold. We also demonstrated that  
31 the  $V_{\text{th}}$  value can be drastically reduced from 3.7 to 0.16 V by increasing the network density.  
32 The physical mechanism involved in the switching of our devices is based on an initial  
33 conduction through tunneling between close Ag fragments, followed by a Schottky emission  
34 across the  $\text{TiO}_2$  coating, which is generated by the Joule effect caused by the initial tunneling  
35 current. This threshold-switching phenomenon in a transparent nanocomposite has a high  
36 interest for neuromorphic computation applications as it can be then integrated into new types  
37 of devices that can be both transparent and flexible.  
38  
39  
40  
41  
42  
43  
44  
45  
46  
47  
48  
49  
50

#### 51 5. Experimental Section

##### 52 *Silver Nanowire networks and Titanium Oxide Deposition*

53 The silver nanowires were kindly provided by the research team of Jean-Pierre Simonato  
54 from CEA-LETI, France, as detailed in Mayousse et al.<sup>[43]</sup>. In terms of dimensions, the AgNWs  
55 present an average diameter of  $79 \pm 10$  nm and an average length of  $7 \pm 3$   $\mu\text{m}$ , while the  
56  
57  
58  
59  
60  
61  
62  
63  
64  
65

1 deposition solution was prepared with a concentration of 0.1 g/L diluted in methanol. As a rigid  
2 substrate, an alkaline 25×25 mm<sup>2</sup> earth boroaluminosilicate glass (Corning 1737) was used,  
3  
4 sonicated during 15 minutes in isopropanol, rinsed with distilled water, and finally dried with  
5 N<sub>2</sub> gas. The fabrication of the AgNW networks was conducted via spray deposition using a  
6  
7 home-made airbrush set-up composed of a spray gun, a robotic arm, and a heating plate. The  
8  
9 automated system uses N<sub>2</sub> as spraying gas with a pressure of 1.4 bar and the substrates were  
10  
11 heated at 110 °C to easily evaporate the solvent. The network density is controlled by adjusting  
12  
13 the number of spray cycles.

14  
15 The TiO<sub>2</sub> films were deposited using a home-made AP-SALD<sup>[44]</sup> using TiCl<sub>4</sub> as titanium  
16  
17 precursor and water as oxygen precursor. The deposition was performed at a substrate  
18  
19 temperature of 150 °C and in the open air. The substrate was placed at a short distance, 150 μm,  
20  
21 from the gas injection head, and was oscillated at a speed of 6.5 cm/s. Our system allows a  
22  
23 uniform deposition of TiO<sub>2</sub> thin films over an area of 50×50 mm<sup>2</sup>. The thickness of the TiO<sub>2</sub>  
24  
25 film was controlled by the number of AP-SALD cycles. The final nanocomposite samples were  
26  
27 then cut and divided into 5×5 mm<sup>2</sup> specimens. Silver-paste-based contacts were manually  
28  
29 deposited at two opposite sides of the specimen and dried for 12 hours in the ambient air. The  
30  
31 resulting distance between the two electrodes in each sample was 4.8 mm.

### 32 33 34 *Characterization techniques and electrical measurements*

35  
36 Scanning Electron Microscopy (SEM) was conducted in a FEI Quanta 250 FE-ESEM  
37  
38 tool, with an energy beam of 10 keV. The areal mass density, which corresponds to the mass of  
39  
40 material per unit surface is measured using SEM micrographs and a plugin of the Software  
41  
42 ImageJ. Transmission electron microscopy (TEM) imaging was obtained with a JEOL JEM  
43  
44 2010 microscope operating at 200 kV (0.19 nm resolution), provided with an EDS system,  
45  
46 INCA Energy TEM 100 X-Max 65T. The sample preparation for TEM imaging was based on  
47  
48 the crushing technique, as the TiO<sub>2</sub> coated AgNWs were removed from the glass substrate using  
49  
50 a spatula and then dropped onto the TEM microgrid.

51  
52 The electrical measurements of the electrode were conducted using a Keithley 2400  
53  
54 source meter using a 2-tip probe station, contacted at the edges of each specimen. The electrical  
55  
56 breakdown was performed by a voltage ramp from 0 to 15 V, with a voltage sweep rate of 24  
57  
58 V/min, similarly, for the first voltage cycle between 0 and 10 V. The threshold bipolar switching  
59  
60 cycles were conducted between 10 V and -10 V, and back to 10V, or 0.4 V to -0.4 V and back  
61  
62 to 0.4 V, with a voltage rate of 100 V/min and 4 V/min, respectively.

## 6. Acknowledgments

This project was supported by the French National Research Agency in the framework of the “Investissements d’avenir” program (ANR-15-IDEX-02) through the project Eco-SESA. This work was also performed within the framework of the Centre of Excellence of Multifunctional Architected Materials “CEMAM” n° AN-10-LABX-44-01. This work was funded by the Agence Nationale de Recherche (ANR, France) via the programs ANR-16-CE05-0021 (DESPATCH), ANR-14-ACHN-0012 (MICROSWITCH) and CE05 INDEED, CE09 MEANING, CE09 PANASSE. This work was as well supported by Région Auvergne Rhône-Alpes through the project Pack Ambition Recherche 2018 Eternité. The Carnot Energies du Futur is acknowledged through the project FREE. David Muñoz-Rojas acknowledges funding through the Marie Curie Actions (FP7/2007-2013, Grant 631111). The authors would like to warmly thank to L. Rapenne, K. Maas and R. Rodríguez-Lamas for fruitful discussions.

Received: ((will be filled in by the editorial staff))

Revised: ((will be filled in by the editorial staff))

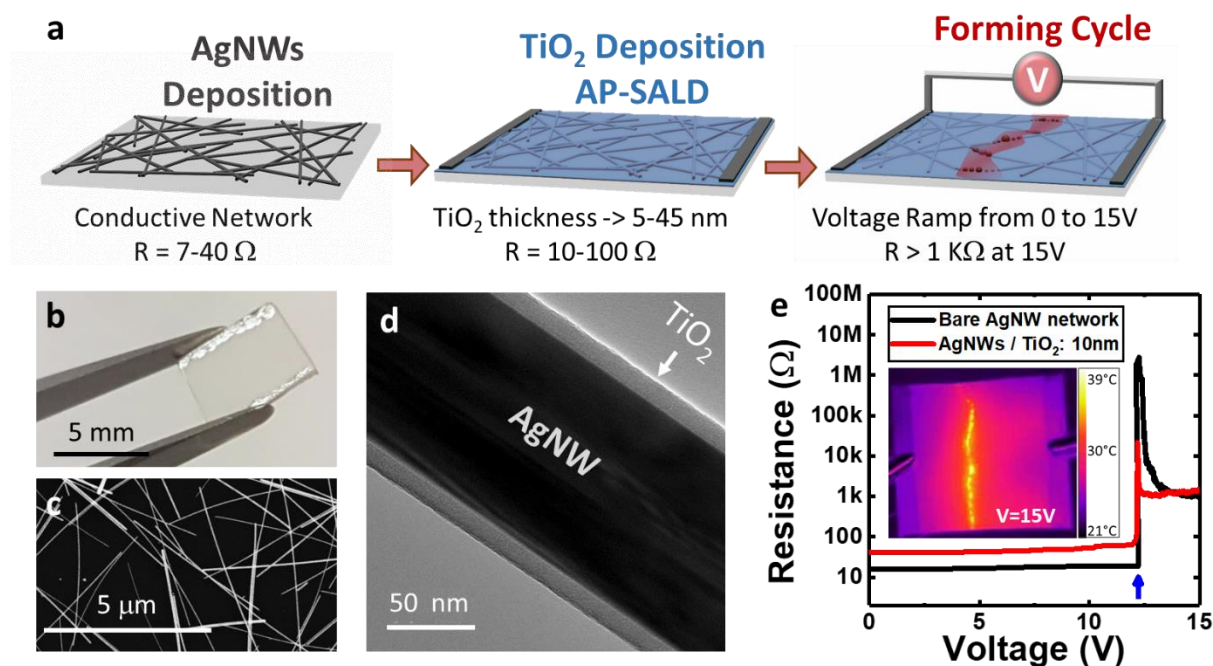
Published online: ((will be filled in by the editorial staff))

## 7. References

- [1] S. Slesazeck, T. Mikolajick, *Nanotechnology* **2019**, *30*, 352003.
- [2] J. J. Yang, D. B. Strukov, D. R. Stewart, *Nature Nanotechnology* **2013**, *8*, 13.
- [3] D. Ielmini, H.-S. P. Wong, *Nature Electronics* **2018**, *1*, 333.
- [4] J. S. Lee, S. Lee, T. W. Noh, *Appl. Phys. Rev.* **2015**, *2*, 031303.
- [5] W. Wang, M. Laudato, E. Ambrosi, A. Bricalli, E. Covi, Y.-H. Lin, D. Ielmini, *IEEE Trans. Electron Devices* **2019**, *66*, 3802.
- [6] J. Yao, J. Lin, Y. Dai, G. Ruan, Z. Yan, L. Li, L. Zhong, D. Natelson, J. M. Tour, *Nat Commun* **2012**, *3*, 1101.
- [7] S. Sorel, D. Bellet, J. N. Coleman, *ACS Nano* **2014**, *8*, 4805.
- [8] D. T. Papanastasiou, A. Schultheiss, D. Muñoz-Rojas, C. Celle, A. Carella, J.-P. Simonato, D. Bellet, *Advanced Functional Materials* **2020**, 1910225.
- [9] F. Guo, N. Li, V. V. Radmilović, V. R. Radmilović, M. Turbiez, E. Spiecker, K. Forberich, C. J. Brabec, *Energy Environ. Sci.* **2015**, *8*, 1690.
- [10] S. Coskun, E. Selen Ates, H. Emrah Unalan, *Nanotechnology* **2013**, *24*, 125202.
- [11] R. Yuksel, E. Ataoglu, J. Turan, E. Alpugan, S. Ozdemir Hacioglu, L. Toppare, A. Cirpan, H. Emrah Unalan, G. Gunbas, *Journal of Polymer Science Part A: Polymer Chemistry* **2017**, *55*, 1680.
- [12] S. I. White, P. M. Vora, J. M. Kikkawa, J. E. Fischer, K. I. Winey, *J. Phys. Chem. C* **2010**, *114*, 22106.
- [13] C.-P. Hsiung, H.-W. Liao, J.-Y. Gan, T.-B. Wu, J.-C. Hwang, F. Chen, M.-J. Tsai, *ACS Nano* **2010**, *4*, 5414.
- [14] S. I. White, P. M. Vora, J. M. Kikkawa, K. I. Winey, *Advanced Functional Materials* **2011**, *21*, 233.

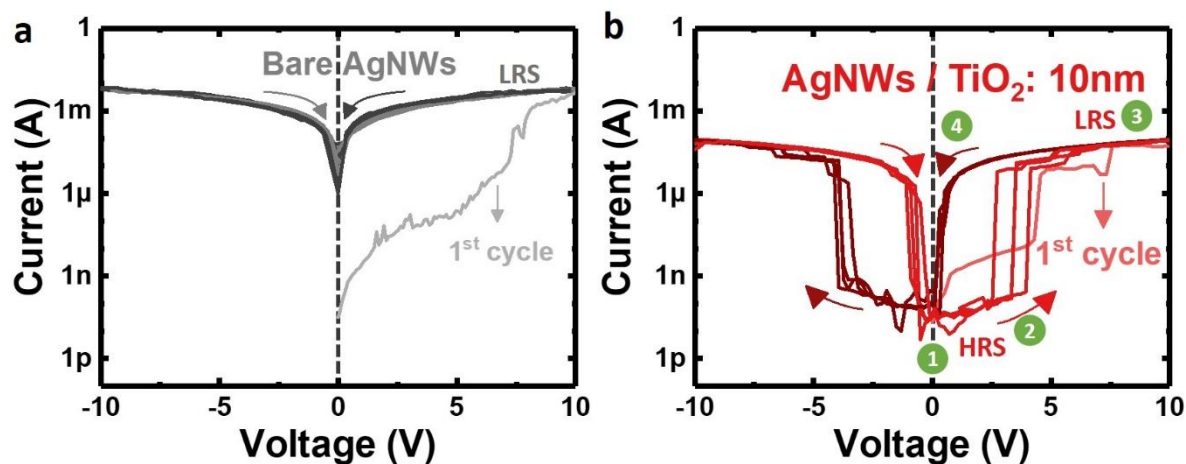
- [15] H. Du, T. Wan, B. Qu, F. Cao, Q. Lin, N. Chen, X. Lin, D. Chu, *ACS Applied Materials & Interfaces* **2017**, *9*, 20762.
- [16] A. Diaz-Alvarez, R. Higuchi, P. Sanz-Leon, I. Marcus, Y. Shingaya, A. Z. Stieg, J. K. Gimzewski, Z. Kuncic, T. Nakayama, *Sci Rep* **2019**, *9*, 14920.
- [17] Q. Li, A. Diaz-Alvarez, R. Iguchi, J. Hochstetter, A. Loeffler, R. Zhu, Y. Shingaya, Z. Kuncic, K. Uchida, T. Nakayama, *Adv. Funct. Mater.* **2020**, 2003679.
- [18] S.-W. Yeom, B. You, K. Cho, H. Y. Jung, J. Park, C. Shin, B.-K. Ju, J.-W. Kim, *Scientific Reports* **2017**, *7*, DOI 10.1038/s41598-017-03746-1.
- [19] T. Wan, Y. Pan, H. Du, B. Qu, J. Yi, D. Chu, *ACS Applied Materials & Interfaces* **2018**, *10*, 2716.
- [20] W. Wang, M. Wang, E. Ambrosi, A. Bricalli, M. Laudato, Z. Sun, X. Chen, D. Ielmini, *Nat Commun* **2019**, *10*, 81.
- [21] H. Sun, Q. Liu, C. Li, S. Long, H. Lv, C. Bi, Z. Huo, L. Li, M. Liu, *Adv. Funct. Mater.* **2014**, *24*, 5679.
- [22] D. P. Langley, M. Lagrange, G. Giusti, C. Jiménez, Y. Bréchet, N. D. Nguyen, D. Bellet, *Nanoscale* **2014**, *6*, 13535.
- [23] M. Lagrange, T. Sannicolo, D. Muñoz-Rojas, B. G. Lohan, A. Khan, M. Anikin, C. Jiménez, F. Bruckert, Y. Bréchet, D. Bellet, *Nanotechnology* **2017**, *28*, 055709.
- [24] T. Sannicolo, N. Charvin, L. Flandin, S. Kraus, D. T. Papanastasiou, C. Celle, J.-P. Simonato, D. Muñoz-Rojas, C. Jiménez, D. Bellet, *ACS Nano* **2018**, *12*, 4648.
- [25] N. Charvin, J. Resende, D. T. Papanastasiou, D. Muñoz-Rojas, C. Jiménez, A. Nourdine, D. Bellet, L. Flandin, *Nanoscale Adv.* **2021**, 10.1039.D0NA00895H.
- [26] D. Muñoz-Rojas, T. Maindrón, A. Esteve, F. Piallat, J. C. S. Kools, J.-M. Decams, *Materials Today Chemistry* **2019**, *12*, 96.
- [27] D. Muñoz-Rojas, H. Sun, D. C. Iza, J. Weickert, L. Chen, H. Wang, L. Schmidt-Mende, J. L. MacManus-Driscoll, *Progress in Photovoltaics: Research and Applications* **2013**, *21*, 393.
- [28] S. Moitzheim, J. E. Balder, P. Poodt, S. Unnikrishnan, S. De Gendt, P. M. Vereecken, *Chem. Mater.* **2017**, *29*, 10007.
- [29] W. Lan, Z. Yang, Y. Zhang, Y. Wei, P. Wang, A. Abas, G. Tang, X. Zhang, J. Wang, E. Xie, *Applied Surface Science* **2018**, *433*, 821.
- [30] A. Khan, V. H. Nguyen, D. Muñoz-Rojas, S. Aghazadehchors, C. Jiménez, N. D. Nguyen, D. Bellet, *ACS Applied Materials & Interfaces* **2018**, *10*, 19208.
- [31] V. H. Nguyen, J. Resende, D. T. Papanastasiou, N. Fontanals, C. Jiménez, D. Muñoz-Rojas, D. Bellet, *Nanoscale* **2019**, *11*, 12097.
- [32] S. Aghazadehchors, V. H. Nguyen, D. Muñoz-Rojas, C. Jiménez, L. Rapenne, N. D. Nguyen, D. Bellet, *Nanoscale* **2019**, *11*, 19969.
- [33] M. Legallais, T. T. T. Nguyen, T. Cazimajou, M. Mouis, B. Salem, C. Ternon, *Materials Chemistry and Physics* **2019**, *238*, 121871.
- [34] H. G. Manning, S. Biswas, J. D. Holmes, J. J. Boland, *ACS Applied Materials & Interfaces* **2017**, *9*, 38959.
- [35] Y. Kim, W. Jeon, M. Kim, J. H. Park, C. S. Hwang, S.-S. Lee, *Applied Materials Today* **2020**, *19*, 100569.
- [36] K. K. Paul, P. K. Giri, *J. Phys. Chem. C* **2017**, *121*, 20016.
- [37] J. Xu, W. Yang, H. Chen, L. Zheng, M. Hu, Y. Li, X. Fang, *J. Mater. Chem. C* **2018**, *6*, 3334.
- [38] E. Lim, R. Ismail, *Electronics* **2015**, *4*, 586.
- [39] M. Hansen, M. Ziegler, H. Kohlstedt, in *2016 IEEE International Conference on Rebooting Computing (ICRC)*, IEEE, San Diego, CA, USA, **2016**, pp. 1–8.
- [40] D. Y. Guo, Z. P. Wu, L. J. Zhang, T. Yang, Q. R. Hu, M. Lei, P. G. Li, L. H. Li, W. H. Tang, *Appl. Phys. Lett.* **2015**, *107*, 032104.

- [41] W. G. Lee, S. I. Woo, J. C. Kim, S. H. Choi, K. H. Oh, *Thin Solid Films* **1994**, 237, 105.  
 [42] Q. Cheng, W. Ahmad, G. Liu, K. Wang, in *2011 11th IEEE International Conference on Nanotechnology*, IEEE, Portland, OR, USA, **2011**, pp. 1598–1601.  
 [43] C. Mayousse, C. Celle, E. Moreau, J.-F. Mainguet, A. Carella, J.-P. Simonato, *Nanotechnology* **2013**, 24, 215501.  
 [44] V. H. Nguyen, D. Bellet, B. Masenelli, D. Muñoz-Rojas, *ACS Applied Nano Materials* **2018**, 1, 6922.

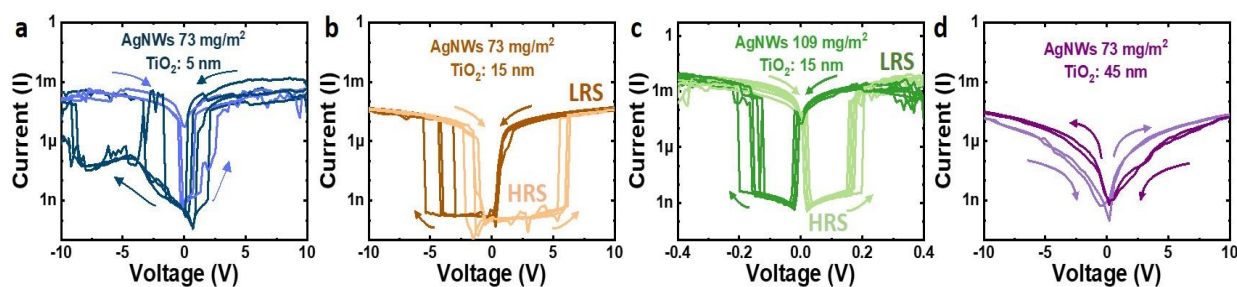


**Figure 1. a.** Schematic of the in-plane threshold switching device fabrication process: AgNWs deposition by airbrush followed by TiO<sub>2</sub> deposition by AP-SALD. The formation of the network crack in red is obtained during an electrical stress test up to 15 V, spanning through the whole sample with a length of 5 mm. **b.** Photo of the as-fabricated device on glass **c.** SEM image of an AgNW network with an *amd* of 80 mg/m<sup>2</sup>. **d.** TEM image of a silver nanowire covered with a 10 nm thick TiO<sub>2</sub> coating. **e.** In situ resistance measurement during an electroforming voltage ramp between 0 and 15 V for a bare AgNW network, in black, and the AgNWs/TiO<sub>2</sub>: 10 nm nanocomposite in red. The blue arrow represents the network breakdown voltage for both samples. Inset of an infrared image of the bare AgNW network for an applied voltage of 15 V after the electrode breakdown, with vertical electrodes placed on opposite edges of the sample.



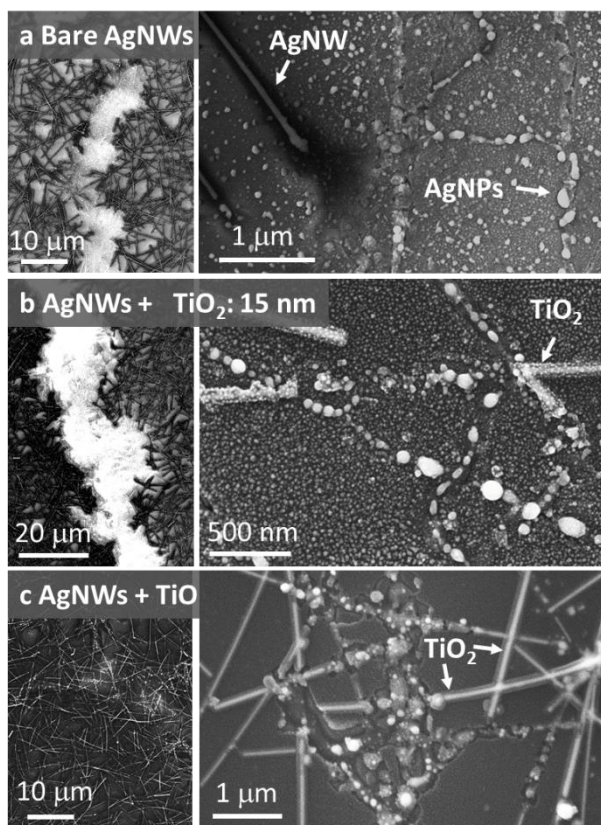


**Figure 2.** I-V cycles for the **a.** bare AgNWs in grey and **b.** AgNWs/TiO<sub>2</sub>:10nm nanocomposite in red. Creation of LRS by a 1st half cycle from 0 to 10 V for the bare AgNW network and the nanocomposite shown in light grey and light red, respectively. Current vs. applied voltage during 4 cycles from -10 V to 10 V, where the numbers 1 to 4 in b. represent the different current stages on the AgNWs/TiO<sub>2</sub> nanocomposite on a cycle from 0 V to 10 V and back to 0V.

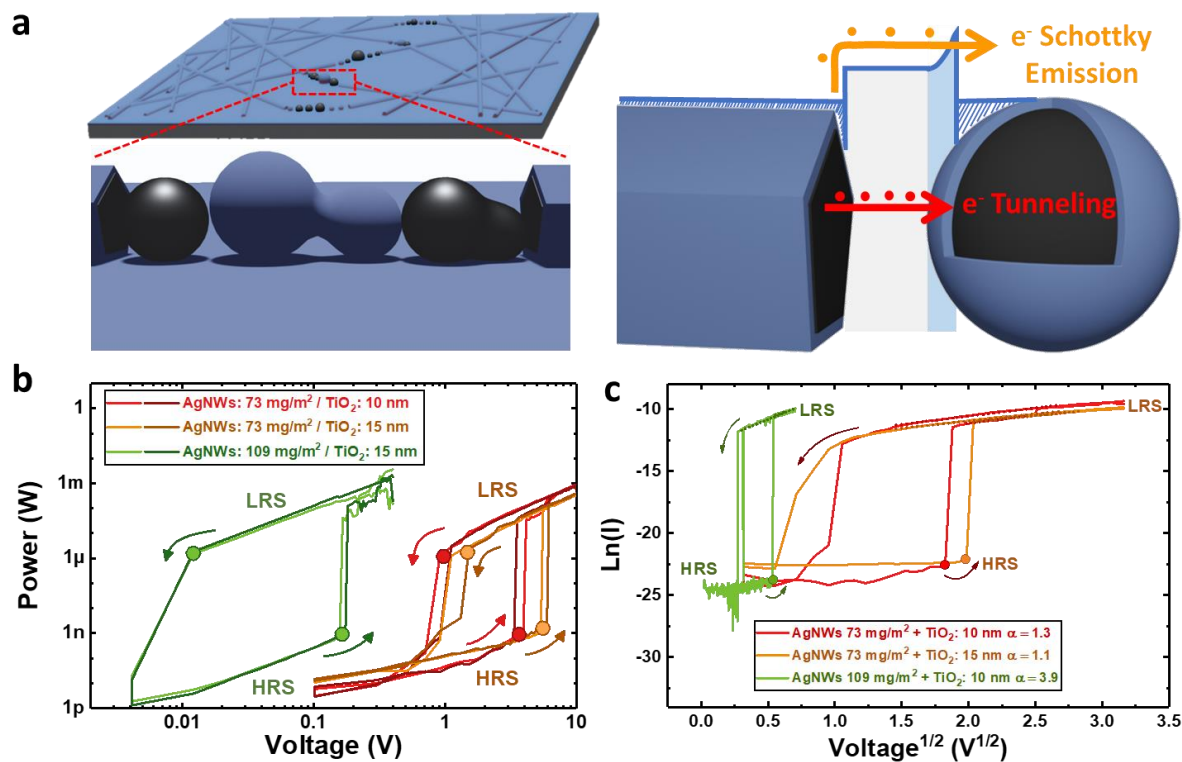


**Figure 3.** I-V curves for AgNWs/TiO<sub>2</sub> nanocomposites with different AgNWs *amd* and TiO<sub>2</sub> thickness: **a.** 4 voltage cycles performed on a 5 nm TiO<sub>2</sub> layer nanocomposite (*amd* = 73 mg/m<sup>2</sup>), **b.** and **c.** 4 voltage cycles on a 15 nm TiO<sub>2</sub> layer nanocomposite for **(b)** sparse network *amd* = 73 mg/m<sup>2</sup> and **(c)** for dense network *amd* = 109 mg/m<sup>2</sup>; **d.** 2 voltage cycles on a 45 nm TiO<sub>2</sub> layer nanocomposite with *amd* = 73 mg/m<sup>2</sup>.





**Figure 4.** Secondary electron SEM images of the crack region in the AgNW network after threshold switching voltage cycles. **a.** bare AgNWs, **b.** AgNWs with a TiO<sub>2</sub> coating of 15 nm and **c.** AgNWs with a TiO<sub>2</sub> coating of 45 nm. General view of the localized crack region (on the left) and a magnified view of the damaged region (on the right).

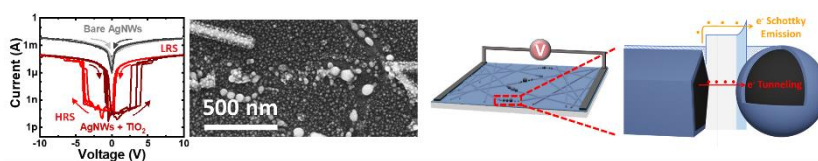


**Figure 5. a.** Scheme of the Threshold Switching mechanism with the formation of Ag nanoparticles between the AgNWs/TiO<sub>2</sub> nanostructures. The gap between particles creates a tunneling potential, while the TiO<sub>2</sub> layer acts as an insulating component, creating a Schottky barrier with the Ag particles. **b.** Power dependence with voltage for three different nanocomposites with variable AgNW density and TiO<sub>2</sub> coating thickness. Red, yellow and green dots represent the voltages where the power abruptly changes, resulting in a resistance state transition. **c.** Schottky relation with voltage following a  $\ln(I)$  vs  $V^{1/2}$  dependence for a cycle for three different AgNWs/TiO<sub>2</sub> nanostructures, with dots representing the transition voltages.  $\alpha$  values represent the slope of the different curves in the LRS

We demonstrate a transparent resistive switching devices entirely fabricated by open-air approaches, without a deposition chamber. The threshold voltage can be tuned by adjusting the density of AgNWs, while maintaining a high LRS/HRS ratio. We show the effect of oxide thickness on the threshold-switching phenomenon, thus shedding light on the conduction mechanism of these type of switching devices.

Joao Resende,<sup>1,2</sup> Abderrahime Sekkat,<sup>1</sup> Viet Huong Nguyen,<sup>3</sup> Tomy Chatin,<sup>1</sup> Carmen Jiménez,<sup>1</sup> Mónica Burriel,<sup>1</sup> Daniel Bellet<sup>1\*</sup>, David Muñoz-Rojas<sup>1\*</sup>

### Planar and Transparent Memristive devices based on Titanium Oxide coated Silver Nanowire Networks with tunable switching voltage

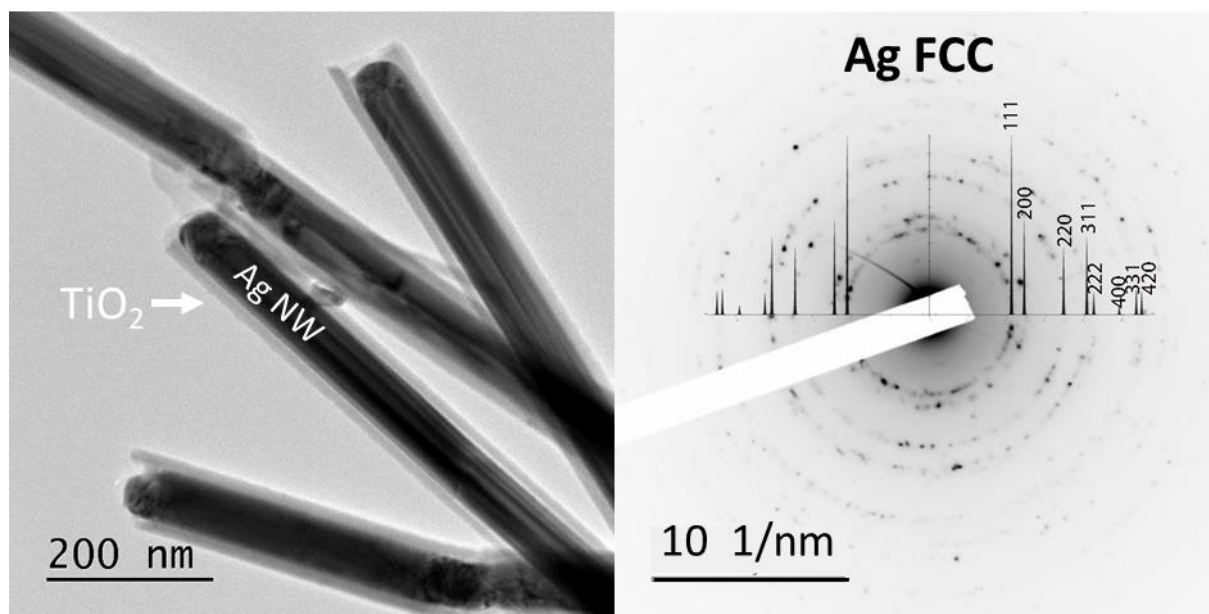


© Copyright 2020. WILEY-VCH GmbH.

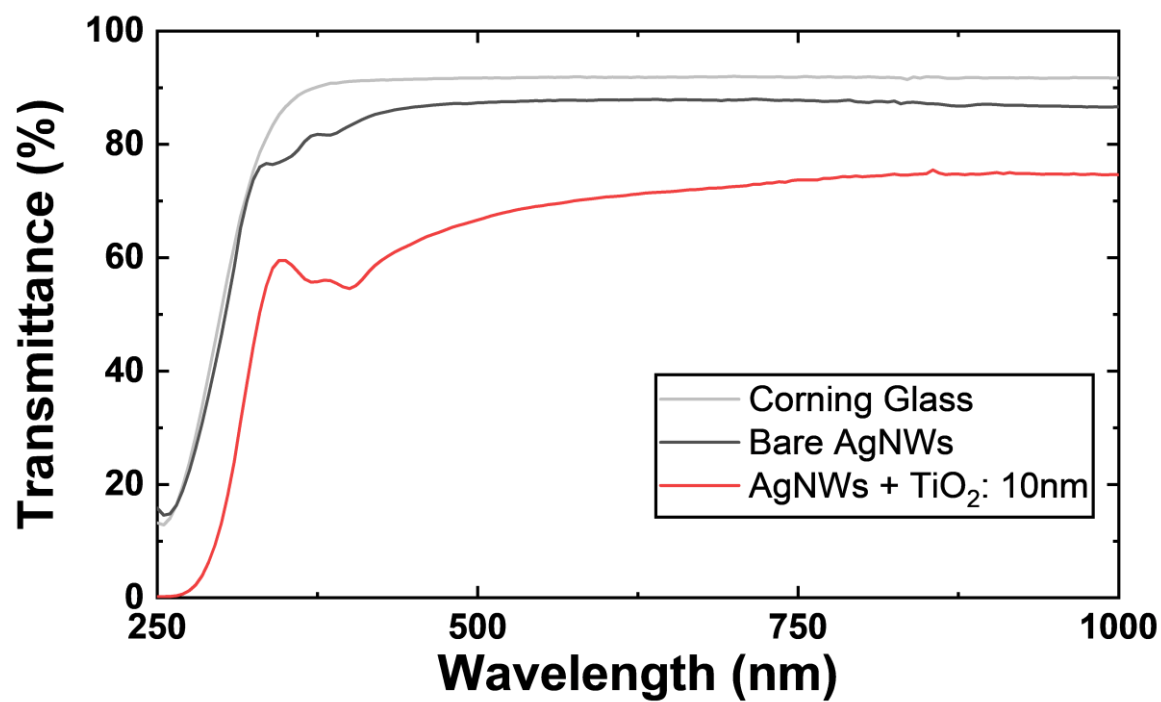
## Supporting Information

### Planar and Transparent Memristive devices based on Titanium Oxide coated Silver Nanowire Networks with tunable switching voltage

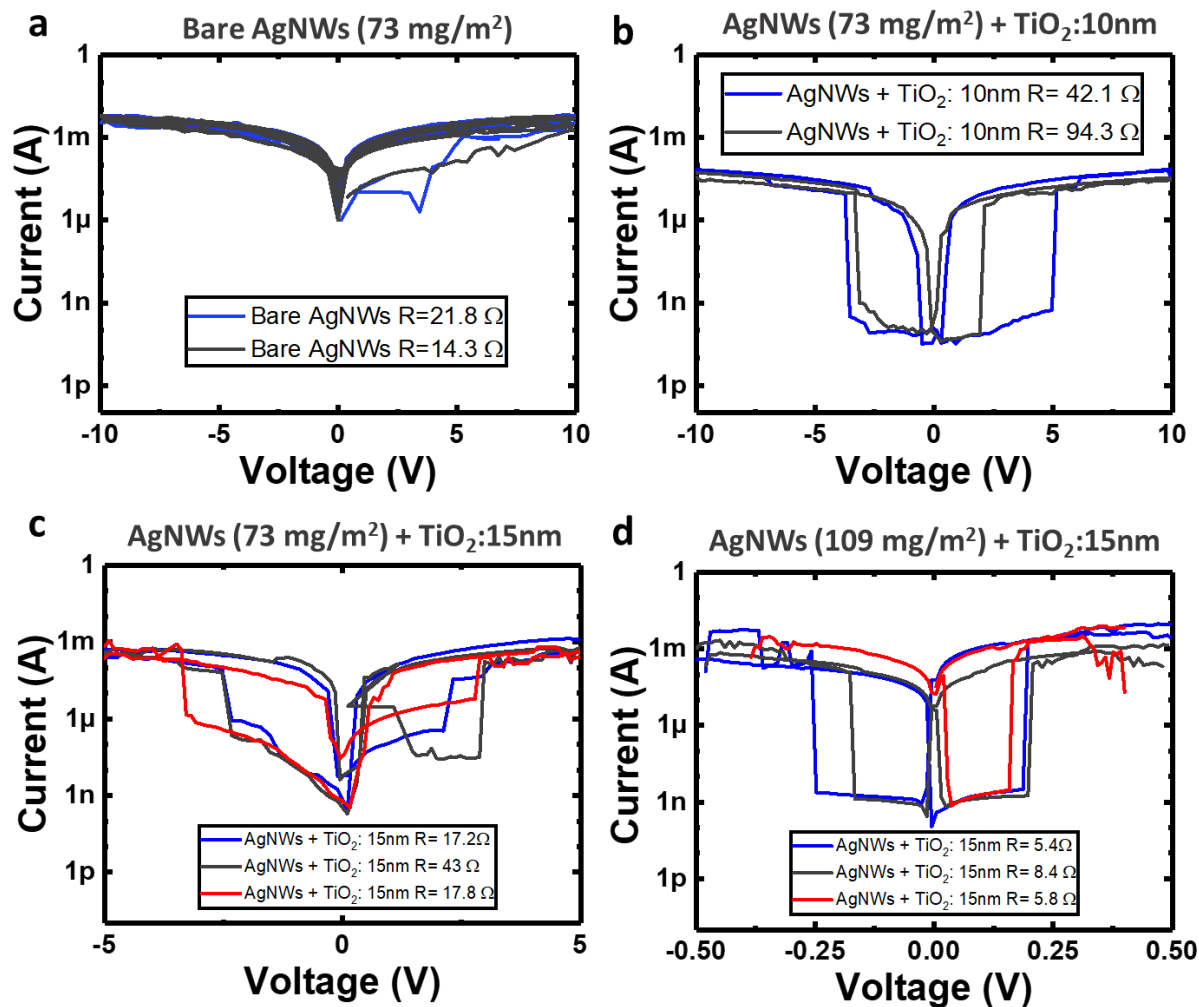
Joao Resende,<sup>1,2</sup> Abderrahime Sekkat,<sup>1</sup> Viet Huong Nguyen,<sup>3</sup> Tomy Chatin,<sup>1</sup> Carmen Jiménez,<sup>1</sup> Mónica Burriel,<sup>1</sup> Daniel Bellet<sup>1\*</sup>, David Muñoz-Rojas<sup>1\*</sup>



**Figure S1.** TEM micrographs and diffraction patterns of AgNWs/TiO<sub>2</sub> nanocomposite. The diffraction pattern confirms the FCC crystalline structure of silver in the nanowires and the amorphous state of TiO<sub>2</sub> films.

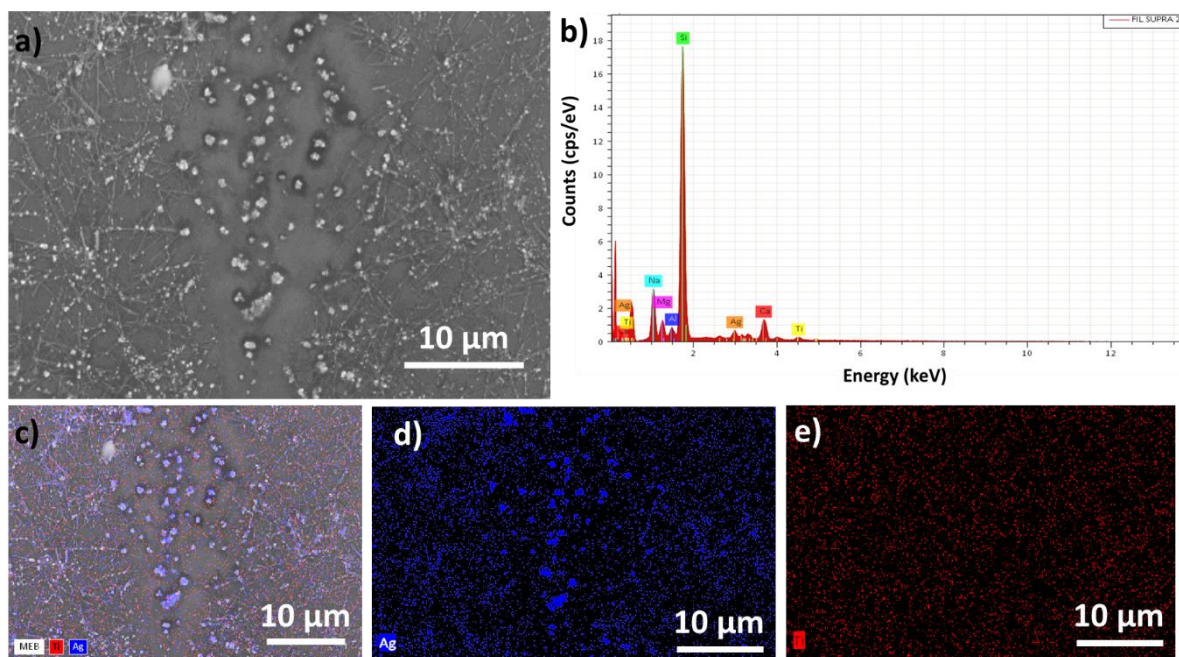


**Figure S2.** Transmittance of corning glass substrate, bare AgNWs and AgNWs/TiO<sub>2</sub> nanocomposite from 250 to 1000nm.



**Figure S3.** I-V curves for different devices of AgNWs/TiO<sub>2</sub> nanocomposites. a. 2 devices of bare AgNWs ( $amd = 73 \text{ mg/m}^2$ ); b. 2 devices AgNWs/TiO<sub>2</sub> nanocomposites ( $amd = 73 \text{ mg/m}^2$  and TiO<sub>2</sub> thickness of 10 nm); c. 3 devices AgNWs/TiO<sub>2</sub> nanocomposites ( $amd = 73 \text{ mg/m}^2$  and TiO<sub>2</sub> thickness of 15 nm) d. 3 devices AgNWs/TiO<sub>2</sub> nanocomposites ( $amd = 109 \text{ mg/m}^2$  and TiO<sub>2</sub> thickness of 15 nm)





**Figure S4.** EDS mapping of AgNWs/TiO<sub>2</sub> nanocomposite with 15 nm TiO<sub>2</sub> layer and dense network  $amd = 109 \text{ mg/m}^2$  a) SEM micrograph, b) EDS spectrum with different elements identified, c) SEM image overlapped with Ag and Ti EDS maps, presented individually in d) and e), respectively.